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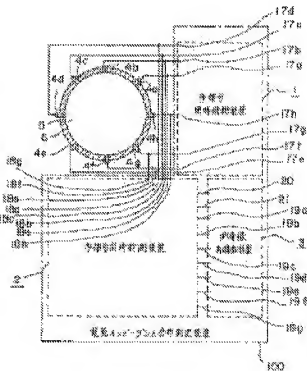
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METHOD AND DEVICE FOR MEASURING ELECTRIC IMPEDANCE DISTRIBUTION

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Abstract of JP 6000168 (A)

PURPOSE: To enhance the accuracy for a reconstruction image by collecting at a high speed potential distribution data used for an electric impedance CT method. **CONSTITUTION:** In the periphery of a measuring object 5, many electrodes 4a-4h are arranged, and from a multi-signal simultaneous supply device 1, electric signals of each different frequency are applied simultaneously to each electrode. A multi-signal simultaneous measuring device 2 measures simultaneously the peripheral potential of the measuring object 5, and a tomographic image reconstructing device 3 executes a frequency analysis of the measured potential, and derives a measured value of a potential distribution in the periphery of the measuring object 5 to each frequency. Subsequently, a tomographic image of an electric impedance distribution for showing an internal state of the measuring object 5 is reconstituted by a numerical calculation.



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